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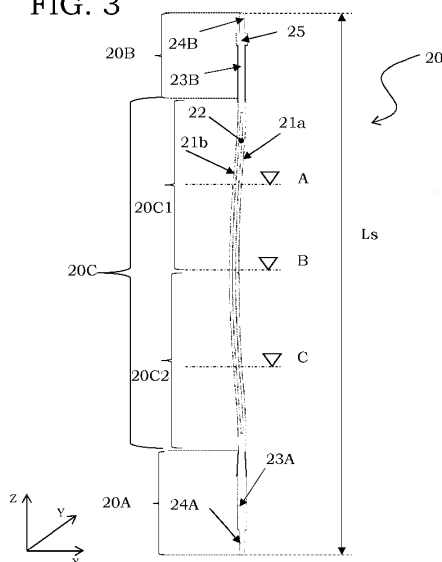
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(54) **Title:** CONTACT PROBE FOR PROBE HEADS OF ELECTRONIC DEVICES

FIG. 3



(57) **Abstract:** It is herein described a contact probe (20) having a first end portion (20A) adapted to abut onto a contact pad of a device under test and a second end portion (20B) adapted to abut onto a contact pad of a PCB board of a testing apparatus, as well as a rod-shaped probe body (20C) extending between said end portions (20A, 20B) along a longitudinal development direction (z) and provided with at least one opening (22) extending along said longitudinal development direction (z) and defines at least one pair of arms (21a, 21b) in said probe body (20C). Suitably, each arm (21a, 21b) of said at least one pair of arms has a not constant transversal section, which is perpendicular to said longitudinal development direction (z), having different areas at different points (A, B, C) along said probe body (20C) so as to ensure a distribution of the stress along the probe body (20C) during the bending thereof during the testing operation of the device under test performed by means of the contact probe (20).

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